# MOSFET – Power, Single, N-Channel, SO-8 FL 30 V, 52 A

#### Features

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### Applications

- CPU Power Delivery
- DC-DC Converters

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	30	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain Current R <sub>θJA</sub> (Note 1)		$T_{A} = 25^{\circ}C$ $T_{A} = 80^{\circ}C$	۱ <sub>D</sub>	16.4 12.3	A
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.51	W
Continuous Drain Current R <sub>θJA</sub> ≤ 10 s (Note 1)		$T_A = 25^{\circ}C$ $T_A = 80^{\circ}C$	۱ <sub>D</sub>	25.3 19.0	A
Power Dissipation $R_{\theta JA} \le 10 \text{ s} \text{ (Note 1)}$	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	6.0	W
Continuous Drain Current R <sub>θJA</sub> (Note 2)		$T_{A} = 25^{\circ}C$ $T_{A} = 80^{\circ}C$	I <sub>D</sub>	9.0 6.8	A
Power Dissipation $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.76	W
Continuous Drain Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> =80°C	۱ <sub>D</sub>	52 39	A
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	PD	25.5	W
Pulsed Drain Current	$T_{A} = 25^{\circ}$	T <sub>A</sub> = 25°C, t <sub>p</sub> = 10 μs		144	Α
Pulsed Source Current (Body Diode)	T <sub>A</sub> = 25°	$T_A = 25^{\circ}C, t_p = 10 \ \mu s$		560	A
Current Limited by Pa	ickage	$T_A = 25^{\circ}C$	I <sub>Dmax</sub>	80	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	°C
Source Current (Body Diode)			ا <sub>S</sub>	23	А
Drain to Source DV/DT			dV/d <sub>t</sub>	7.0	V/ns
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, V <sub>GS</sub> = 10 V, I <sub>L</sub> = 29 A <sub>pk</sub> , L = 0.1 mH, R <sub>GS</sub> = 25 $\Omega$ ) (Note 3)			E <sub>AS</sub>	42	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

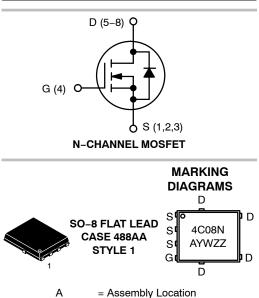
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.

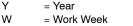


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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	5.8 mΩ @ 10 V	52 A
30 V	8.5 mΩ @ 4.5 V	52 A





ZZ = Lot Traceability

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4C08NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4C08NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum rating. Parts are 100% tested at  $T_J = 25^{\circ}$ C,  $V_{GS} = 10$  V,  $I_L = 21$  Apk,  $E_{AS} = 22$  mJ.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ extsf{ heta}JC}$	4.9	
Junction-to-Ambient - Steady State (Note 4)	$R_{\thetaJA}$	49.8	°C 444
Junction-to-Ambient - Steady State (Note 5)	$R_{\thetaJA}$	164.6	°C/W
Junction-to-Ambient – (t $\leq$ 10 s) (Note 4)	$R_{\thetaJA}$	21.0	

4. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.

5. Surface-mounted on FR4 board using the minimum recommended pad size.

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, I <sub>D</sub> = 250 $\mu$ A		30			V
Drain-to-Source Breakdown Voltage (transient)	V <sub>(BR)DSSt</sub>	$V_{GS}$ = 0 V, $I_{D(aval)}$ = 8.4 A, $T_{case}$ = 25°C, $t_{transient}$ = 100 ns		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				13.8		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$			1.0	μΑ
		$V_{DS} = 24 V$	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	s = ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							-
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 250 \ \mu A$		1.3		2.1	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.9		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 18 A		4.6	5.8	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		6.8	8.5	
Forward Transconductance	9fs	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			42		S
Gate Resistance	R <sub>G</sub>	T <sub>A</sub> = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				1113	1670	pF
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MH	lz, V <sub>DS</sub> = 15 V		702		
Reverse Transfer Capacitance	C <sub>RSS</sub>				39		1
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15 V, f = 1 MHz			0.035		
Total Gate Charge	Q <sub>G(TOT)</sub>				8.4		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			1.8		nC
Gate-to-Source Charge	Q <sub>GS</sub>				3.5		
Gate-to-Drain Charge	Q <sub>GD</sub>				3.3		
Gate Plateau Voltage	V <sub>GP</sub>				3.4		V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			18.2		nC

#### SWITCHING CHARACTERISTICS (Note 7)

6. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

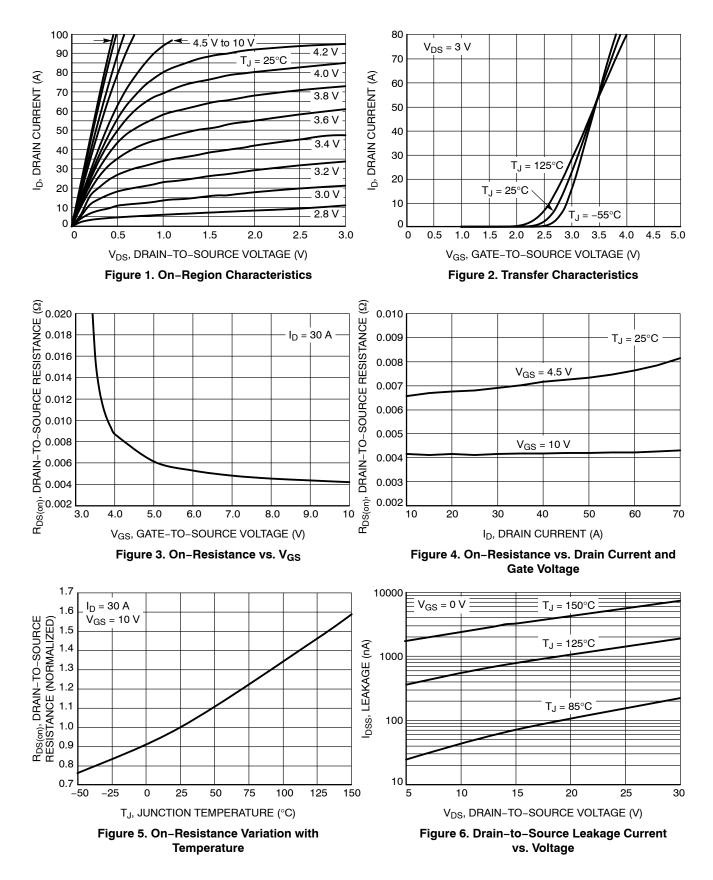
7. Switching characteristics are independent of operating junction temperatures.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

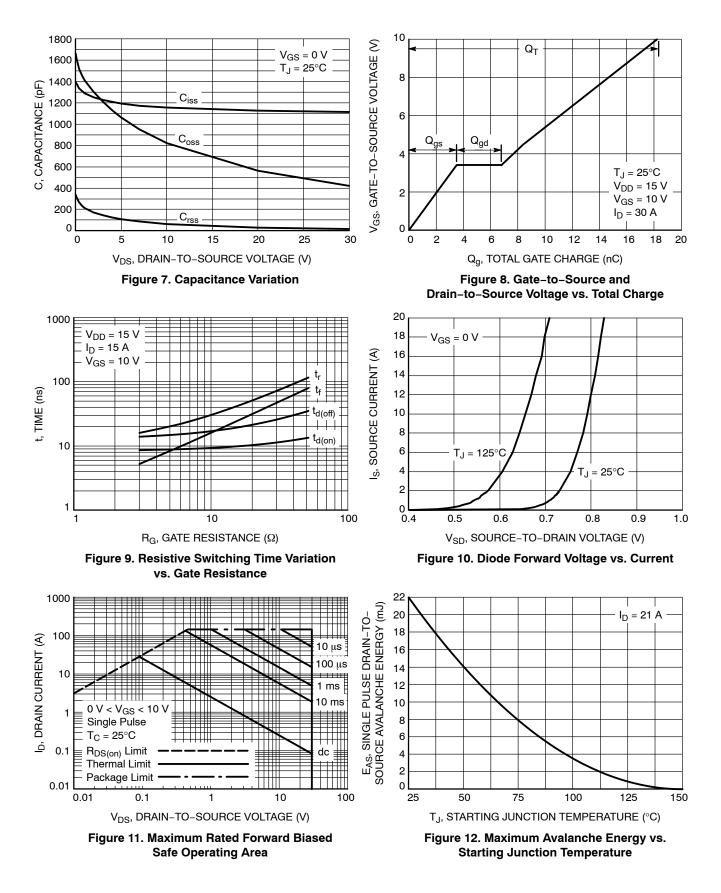
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	lote 7)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, I <sub>D</sub> = 15 A, R <sub>G</sub> = 3.0 $\Omega$			9.0		ns
Rise Time	t <sub>r</sub>				33		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				15		
Fall Time	t <sub>f</sub>				4.0		
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, I <sub>D</sub> = 15 A, R <sub>G</sub> = 3.0 Ω			7.0		ns
Rise Time	t <sub>r</sub>				26		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				19		
Fall Time	t <sub>f</sub>				3.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.79	1.1	v
		I <sub>S</sub> = 10 A	T <sub>J</sub> = 125°C		0.66		v
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 30 A			28.3		
Charge Time	t <sub>a</sub>				14.5		ns
Discharge Time	t <sub>b</sub>				13.8		
Reverse Recovery Charge	Q <sub>RR</sub>				15.3		nC

 $\begin{array}{ll} \mbox{6. Pulse Test: pulse width } \le 300 \ \mu \mbox{s, duty cycle } \le 2\%. \\ \mbox{7. Switching characteristics are independent of operating junction temperatures.} \end{array}$ 

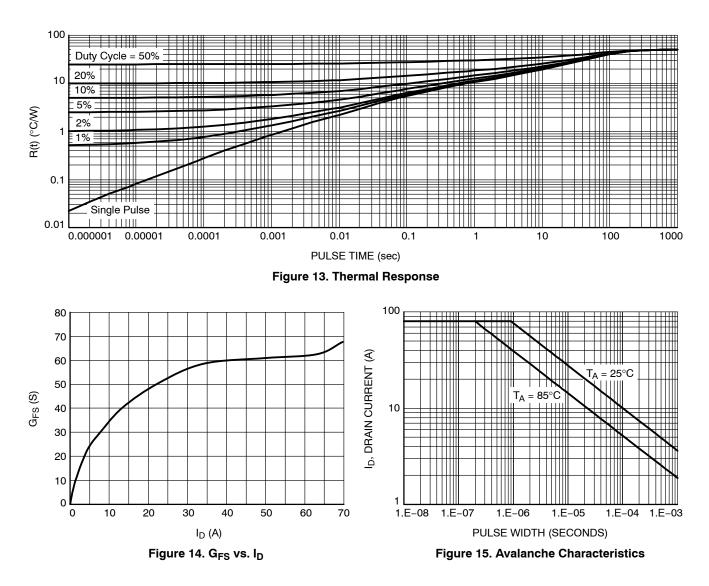
### **TYPICAL CHARACTERISTICS**



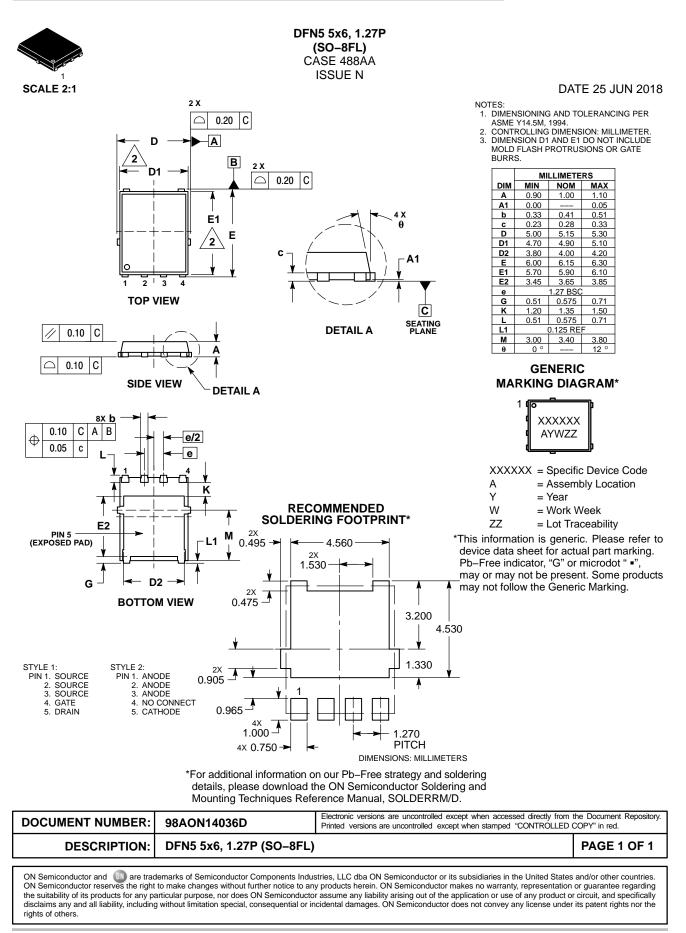
### **TYPICAL CHARACTERISTICS**



### **TYPICAL CHARACTERISTICS**







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